

# Dual Channel x1 PCle Redriver/Equalizer

Check for Samples: SN65LVPE501

### **FEATURES**

- Single Lane PCle Equalizer/Redriver
- Support for Both PCle Gen I (2.5Gbps) and Gen II (5.0 Gbps) Speed
- Selectable Equalization, De-emphasis and Output Swing Control
- Integrated Termination
- Hot-Plug Capable
- Receiver Detect
- Low Power:
  - 330mW(TYP),  $V_{CC} = 3.3V$
- Auto Low Power Modes:
  - 5mW (TYP) When no Connection Detected
  - 70mW (TYP) When in Auto-Low Power Mode

- Excellent Jitter and Loss Compensation Capability:
  - 30" of 6 mil Stripline on FR4
- Small Foot Print 24 Pin 4 x 4 QFN Package
- High Protection Against ESD Transient

HBM: 3,000 VCDM: 1,500 VMM: 200 V

#### **APPLICATIONS**

 PC MB, Docking Stations, Backplane and Cabled Application

## **DESCRIPTION**

The SN65LVPE501 is a dual channel, single lane PCIe redriver and signal conditioner supporting data rates of up to 5.0Gbps. The device complies with PCIe spec revision 2.1.

### Programmable EQ, De-Emphasis and Amplitude Swing

The SN65LVPE501 is designed to minimize the signal degradation effects such as crosstalk and inter-symbol interference (ISI) that limits the interconnect distance between two devices. The input stage of each channel offers selectable equalization settings that can be programmed to match loss in the channel. The differential outputs provide selectable de-emphasis to compensate for the anticipated distortion PCIe signal will experience. Level of de-emphasis will depend on the length of interconnect and its characteristics. Both equalization and de-emphasis levels are controlled by the setting of signal control pins EQ1, EQ2 and DE1, DE2.

To provide additional control of signal integrity in extended backplane applications LVPE501 provides independent output amplitude control for each channel. See Table 2 for setting details.

#### **Device PowerOn**

Device initiates internal power-on reset after  $V_{CC}$  has stabilized. External reset can also be applied at anytime by toggling RST pin. External reset is recommended after every device power-up. When RST is driven high, the device samples the state of EN\_RXD, if it is set H device enters Rx.Detect state where each channel will perform Rx.Detect function (as described in PCle spec). If EN\_RXD is set L, automatic RX detect function is disabled and both channels are enabled with their termination set to  $Z_{DC\_RX}$ .

#### **Receiver Detection**

While EN\_RXD pin is H and device is not in sleep mode ( $\overline{RST}$  is H), SN65LVPE501 performs RX.Detect on both channels indefinitely until remote termination is detected on both channels. Automatic Rx detection feature can be forced off by driving EN\_RXD low. In this state both channels input termination are set to  $Z_{DC_RX}$ .



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

### **DESCRIPTION CONTINUED**

### Sleep (Shut\_Down) Mode

This is low power state triggered by  $\overline{RST}$  = L. In sleep mode receiver termination resistor for each of the two channels is switched to  $Z_{RX-HIGH\_IMP}$  of >50 K $\Omega$  and transmitters are pulled to Hi-Z state. Device power is reduced to <1mW (TYP). To get device out of sleep mode  $\overline{RST}$  is toggled L-H.

### **Electrical Idle Support**

A link is in an electrical idle state when the TX $\pm$  voltage is held at a steady constant value like the common mode voltage. SN65LVPE501 detects an electrical idle state when RX $\pm$  input voltage of the associated channel falls below  $V_{EID\_TH}$  min. After detection of an electrical idle state in a given channel the device asserts electrical idle state in its corresponding TX. When RX $\pm$  voltage exceeds  $V_{EID\_TH}$  max, normal device operation is restored and output starts passing input signal. Electrical idle exit and entry time is specified at  $\leq$ 6ns.

Electrical idle support is independent for each channel.

#### **Power Save Features**

The device supports three power save modes as described below.

1. Sleep (Shut Down) Mode

This mode can be enabled from any state (Rx detect or active) by driving  $\overline{RST}$  L. In this state both channels have their termination set to  $Z_{RX-HIGH\ IMP+}$  and outputs are at Hi-Z. Device power is 1mW (MAX)

2. Auto Low Power Mode

This mode is enabled when PS pin is tied H and device is in active mode. In this mode anytime  $Vin_{diff\_pp}$  falls below selected  $V_{EID\_TH}$  for a *given channel* and stays below  $V_{EID\_TH}$  for >1µs (TYP), the associated CH will enter auto low power (ALP) mode where power/CH will be reduced to <1/3<sup>rd</sup> of normal operating power/CH or about 70mW under typical voltage of 3.3V when ALP conditions are met for both channels. A CH will exit ALP mode whenever  $Vin_{diff\_pp}$  exceeds max  $V_{EID\_TH}$  for that channel. Exit latency is 30ns max. To use this mode link latency will need to account for the ALP exit time for N\_FTS. ALP mode is handled by each channel independently based on its input differential signal level. This mode can be disabled by leaving PS as NC or tying PS to GND via  $4.7k\Omega$ .

3. Cable Disconnect Mode

This mode is activated when  $\overline{RST}$  is H,  $EN_RXD = H$ , and no termination is detected by either channel. Device is in the Rx.Detect state whereby it is continuously performing Rx.Detect on both channels. In this state total power consumed by device is typically <3% of normal active power. Or <10mW (MAX).

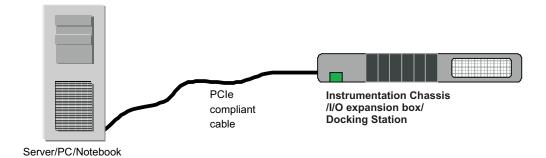
### **Beacon Support**

With its broadband design, the SN65LVPE501 supports low frequency Beacon signal (as defined by PCIe 2.1 spec) used to indicate wake-up event to the system by a downstream device when in L2 power state. All requirements for a beacon signal as specified in PCI Express specification 2.1 must be met for device to pass beacon signals.

#### **Devic Power**

The SN65LVPE501 is designed to operate from a single 3.3V supply. Always practice proper supply sequencing procedure. Apply  $V_{CC}$  first before any input control pin signals are applied to the device. Power-down sequence is in reverse order.





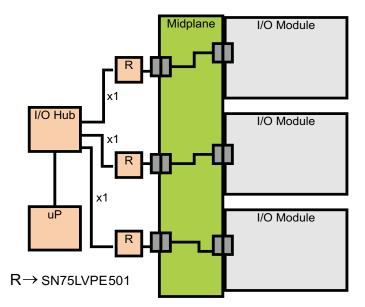


Figure 1. SN65LVPE501 Typical Applications



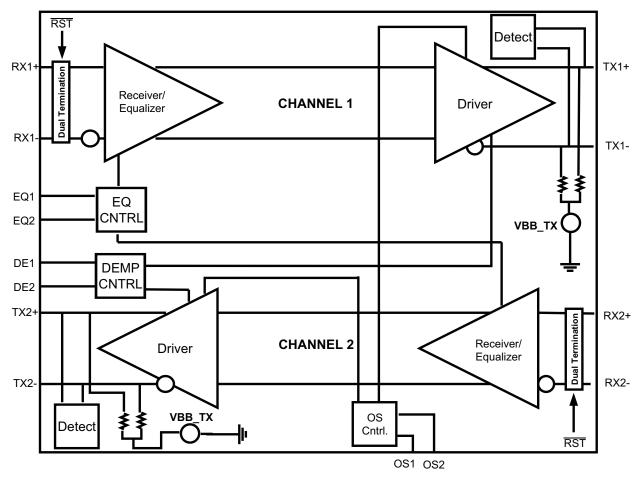
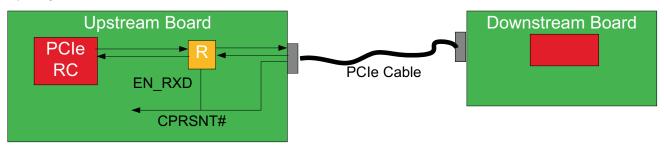


Figure 2. Data Flow Block Diagram

## **Split System**



## **Enclosed System**

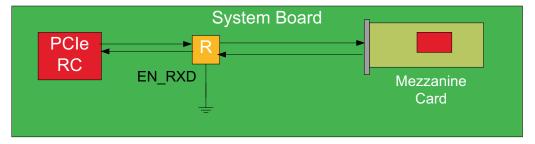


Figure 3. Typical Implementation



## **Table 1. Pin Description**

P	IN							
NUMBER	NAME	I/O TYPE	DESCRIPTION					
HIGH SPEED	DIFFERENTI	AL I/O PINS						
8	RX1+	I, CML						
9	RX1-	I, CML	Non-inverting and inverting CML differential input for CH 1 and CH 2. These pins are tied to an					
20	RX2+	I, CML	internal voltage bias by dual termination resistor circuit.					
19	RX2-	I, CML						
23	TX1+	O, CML						
22	TX1-	O, CML	Non-inverting and inverting CML differential output for CH 1 and CH 2. These pins are					
11	TX2+	O, CML	internally tied to voltage bias by termination resistors.					
12	TX2-	O, CML						
DEVICE CON	TROL PIN <sup>(1)</sup>	<u> </u>						
5	EN_RXD	I, LVCMOS	Sets device operation modes per Table 2. Internally pulled to VCC					
14	PS	I, LVCMOS	Select auto-low power save mode per Table 2. Internally pulled to GND					
7	RST	I, LVCMOS	Reset device, input active Low. Internally pulled to VCC					
24	RSVD	I, LVCMOS	Reserved for factory test. Must be connected to GND					
SIGNAL CON	TROL PINS <sup>(2</sup>	2)						
3,16	DE1, DE2	I, LVCMOS	Selects de-emphasis settings for CH 1 and CH 2 per Table 2. Internally tied to V <sub>CC</sub> /2					
2,17	EQ1, EQ2	I, LVCMOS	Selects equalization settings for CH 1 and CH 2 per Table 2. Internally tied to V <sub>CC</sub> /2					
4, 15	OS1, OS2	I, LVCMOS	Selects output amplitude for CH 1 and CH 2 per Table 2. Internally tied to V <sub>CC</sub> /2					
POWER PINS	3	•						
1,13	VCC	Power	Positive supply should be 3.3V ± 10%					
6,10,18,21	GND	Power	Supply ground					

When not used can be left as NC or connected to  $V_{CC}/GND$  via  $4.7k\Omega$  resistor. Internally biased to  $V_{CC}/2$  with >200k $\Omega$  pullup/pulldown. When 3-state pins are left as NC board leakage at the pin pad must be <1  $\mu$ A otherwise drive to  $V_{CC}/2$  to assert mid-level state.

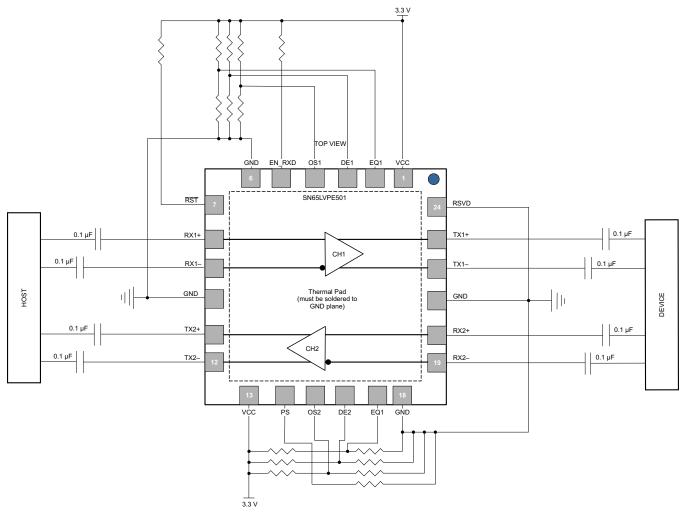


**Table 2. Signal Control Pin Setting** 

0	Sx	TRANSITION BIT AMPLITUDE (TYP mVpp)				
N	IC	1000				
	0	87	75			
	1	11	00			
DEx <sup>(1)</sup>	OSx <sup>(1)</sup> = NC	$OSx^{(1)} = 0$	OSx <sup>(1)</sup> = 1			
NC	−3.7 dB	-2.5 dB	-4.6 dB			
0	-6.4 dB	-5.5 dB	-6.6 dB			
1	-9.4 dB	-9.5 dB	-8.7 dB			
EQ	x <sup>(1)</sup>		ATION dB I Speed)			
N	IC	(	)			
(	0	7				
	1	15				
EN_	RXD	DEVICE FUNCTION				
	0	Set input termination to Z <sub>DC_RX</sub> and disable Rx. Detect				
	1	Perform Rx.Detect (default, internally pulled to Vcc)				
R	ST	DEVICE F	UNCTION			
-	0		scent state and et to Hi-Z			
	1	Device not in shut_down mode (default, internally pulled to Vcc)				
P	'S	DEVICE F	UNCTION			
	0	Auto-low power mode disabled (default, internally pulled to GND)				
	1	Auto-low power mode enabled				

<sup>(1)</sup> Applies to Channel 1 and Channel 2 at 2.5 GHz.





- (1) This is a reference example and it is not intended to represent the best configuration; every designer should select the EQ and DE settings that better fits the system needs. All DEx, EQx and OSx pins default to NC.
- (2) The recommended value for all the resistors shown in the Figure is 4.9K  $\Omega$ .
- (3) For terminals OSx, DEx, and EQx, populate only pull-up or only pull-down according to the desired setting.

Figure 4. Reference Device Implementation



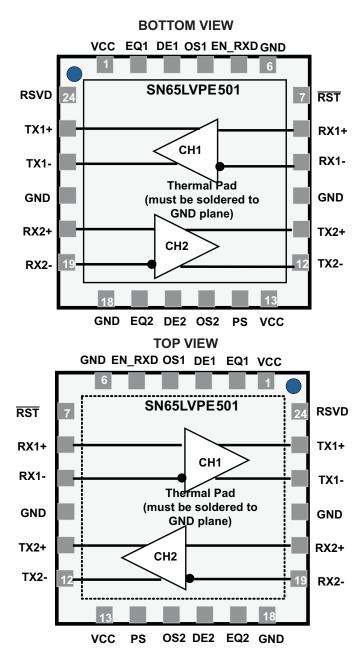


Figure 5. Flow-Through Pin-Out

### ORDERING INFORMATION(1)

PART NUMBER	PART MARKING	PCAKAGE
SN65LVPE501RGER	LVPE501	24-pin RGE Reel (large)
SN65LVPE501RGET	LVPE501	24-pin RGE Reel (small)

<sup>(1)</sup> For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.



### **ABSOLUTE MAXIMUM RATINGS**

over operating free-air temperature range (unless otherwise noted)(1)

		UNIT / VALUES		
Supply Voltage Range (2)	V <sub>CC</sub>	−0.5 V to 4 V		
Voltage Range	Differential I/O	-0.5V to 4 V		
Vollage Range	Control I/O	-0.5 V to V <sub>CC</sub> + 0.5		
	(Human Body Model) QSS 009-105 (JESD22-A114B)	±3000 V		
Electrostatic Discharge	(Charged Device Model) QSS 009-147 (JESD22-C101-A)	±1500 V		
	(Machine Model) JESD22-A115-A	±200 V		
Continuous power dissipation		See Thermal Information Table		

<sup>(1)</sup> Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### THERMAL INFORMATION

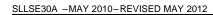
		SN65LVPE501	
	THERMAL METRIC <sup>(1)</sup>	RGE	UNITS
		24 PINS	
$\theta_{JA}$	Junction-to-ambient thermal resistance <sup>(2)</sup>	46	
$\theta_{\text{JC(TOP)}}$	Junction-to-case(top) thermal resistance (3)	42	
$\theta_{JB}$	Junction-to-board thermal resistance (4)	13	9000
Ψлт	Junction-to-top characterization parameter (5)	0.5	°C/W
ΨЈВ	Junction-to-board characterization parameter (6)	9	
$\theta_{\text{JC(BOTTOM)}}$	Junction-to-case(bottom) thermal resistance (7)	4	

- (1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.
- (2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.
- (3) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific JEDEC-standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.
- (4) The junction-to-board thermal resistance is obtained by simulating in an environment with a ring cold plate fixture to control the PCB temperature, as described in JESD51-8.
- (5) The junction-to-top characterization parameter, ψ<sub>JT</sub>, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ<sub>JA</sub>, using a procedure described in JESD51-2a (sections 6 and 7).
- (6) The junction-to-board characterization parameter, ψ<sub>JB</sub>, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ<sub>JA</sub>, using a procedure described in JESD51-2a (sections 6 and 7).
- 7) The junction-to-case (bottom) thermal resistance is obtained by simulating a cold plate test on the exposed (power) pad. No specific JEDEC standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.

Copyright © 2010–2012, Texas Instruments Incorporated

Submit Documentation Feedback

<sup>(2)</sup> All voltage values, except differential voltages, are with respect to network ground terminal.





### **RECOMMENDED OPERATING CONDITIONS**

over operating free-air temperature range (unless otherwise noted)

		MIN	TYP	MAX	UNIT
V <sub>CC</sub>	Supply Voltage	3	3.3	3.6	V
C <sub>COUPLING</sub>	AC Coupling Capacitor	75		200	nF
	Operating free-air temperature	-40		85	°C

### **ELECTRICAL CHARACTERISTICS**

over operating free-air temperature range (unless otherwise noted)

•	g free-air temperature range (  PARAMETER		T CONDITIONS	MIN	TYP	MAX	UNIT
DEVICE BARA				IVIIIV	IIF	IVIAA	UNII
DEVICE PARAI	METERS (under recommended opera		•			ı	
I <sub>CC</sub>		RST, DEx, EQx, OSx = NC, E $V_{ID} = 1000 \text{mV}_{p-p}$		101	120		
ICC <sub>idle</sub>	Supply Current	PS=1; When auto-low power of	conditions are met		21	26	mA
ICC <sub>shut-down</sub>		RST = GND			0.2	1	
ICC <sub>RX.Detect</sub>		$\overline{RST}$ , EN_RXD = NC			2		l
	Maximum Data Rate					5	Gbps
AutoLP <sub>ENTRY</sub>	Auto Low Power Entry Time	Electrical Idle at Input, Refer t	o Figure 9	1.0	1.3		μs
AutoLP <sub>EXIT</sub>	Auto Low Power Exit Time	After first signal activity, Refer	to Figure 9		15	30	ns
t <sub>PU</sub>	Power Up Time	Rx Detect Start Event, Vcc = RST, EN_RXD = H	Stable		15	30	μs
t <sub>DIS</sub>	Sleep (shut-down) Mode Entry Time	RST H→L; EN_RXD=X				1	μs
T <sub>ENB</sub>	Sleep (shut-down) Mode Exit Time	RST L→H; EN_RXD=H, Start	of Ex detect event			10	μs
CONTROL LO	GIC (under recommended operating of	conditions, unless otherwise	noted)				
V <sub>IH</sub>	High level Input Voltage		1.4		$V_{CC}$	V	
V <sub>IL</sub>	Low Level Input Voltage		-0.3		0.5	V	
V <sub>HYS</sub>	Input Hysteresis			150		mV	
	High Level Innut Current	OSx, EQx, DEx = V <sub>CC</sub>			30		
I <sub>IH</sub>	High Level Input Current	$EN_RXD$ , $\overline{RST} = V_{CC}$			1	μA	
		OSx, EQx, DEx = GND	-30				
$I_{\rm IL}$	Low Level Input Current	PS = GND	-1			μA	
		$EN_RXD$ , $\overline{RST} = GND$	-20				
RECEIVER AC	/DC (under recommended operating	conditions, unless otherwise	noted)				
Vin <sub>diff pp</sub>	RX1, RX2 Input Voltage Swing	AC coupled differential signal		100		1200	mVp-p
V <sub>CM_RX</sub>	RX1, RX2 Common Mode Voltage			0		3.6	٧
Vin <sub>COM_P</sub>	RX1, RX2 AC Peak common mode voltage					150	mVP
Z <sub>DC_RX</sub>	DC single ended impedance			40	50	60	Ω
Z <sub>diff_RX</sub>	DC Differential Input impedance			80	100	120	Ω
Z <sub>RX_High_IMP+</sub>	DC Input High Impedance		Device in sleep mode Rx termination not powered; Measured with respect to GND over 200mV max				kΩ
V <sub>EID_TH</sub>	Electrical Idle Detect Threshold	Measured at receiver pin (see	Measured at receiver pin (see Figure 7)				mVpp
		50 MHz – 1.25 GHz		10			dB
RL <sub>RX-DIFF</sub>	Differential Return Loss	4.05.011 0.5.011	Operating temperature 0°C to 85°C	8			i
		1.25 GHz – 2.5 GHz	Operating temperature –40°C to 85°C	7			dB
RL <sub>RX-CM</sub>	Common Mode Return Loss	50 MHz – 2.5 GHz	+	10			dB

Submit Documentation Feedback

Copyright © 2010–2012, Texas Instruments Incorporated



# **ELECTRICAL CHARACTERISTICS (continued)**

	free-air temperature range (		ST CONDITIONS	MINI	TVD	MAY	UNIT
TD 4 NO				MIN	TYP	MAX	UNII
TRANSMITTER A	AC/DC (under recommended opera	1	•				
		$R_L = 100\Omega \pm 1\%$ , DEx, OS = 1	·	800	1000	1200	
$V_{TXDIFF\_PP}$		$R_L = 100\Omega \pm 1\%$ , DEx = NC, 0			875		mV
		$R_L = 100\Omega \pm 1\%$ , DEx = NC, 0	OSx = VCC Transition Bit		1100		
	Differential peak-to-peak Output Voltage	$R_L$ =100 $\Omega$ ±1%, DEx=NC, O Non-Transition Bit	Sx = 0,1,NC		655		
V <sub>TXDIFF_NTB_PP</sub>		$R_L$ =100 $\Omega$ ±1%, DEx=0,OSx Non-Transition Bit	= 0,1,NC		495		mV
		R <sub>L</sub> =100Ω ±1%, DEx=1, OS> NC Non-Transition Bit	ζ = 0,1,		350		
		DEx, OSx = NC, See	Operating temperature 0°C to 85°C	-3.0	-3.7	-4.0	
	De-Emphasis Level	Figure 11; (for OS1,2 = 1 and 0 see Table 2)	Operating temperature –40°C to 85°C	-3.0	-3.7	-4.2	dB
	·	DEx = 0, OSx = NC			-6.4		
		DEx = 1, OSx = NC			-9.4		dB
T <sub>DE</sub>	De-Emphasis Width	At 5Gbps			0.8		UI
Z <sub>diff_TX</sub>	DC Differential Impedance	Defined during signaling		80	100	120	Ω
<u>-αιπ_1 x</u>	Do Billotottiai Impodatioo	Domina during digitating	Operating temperature 0°C to 85°C	10	100	120	
		f = 50 MHz – 1.25 GHz.	Operating temperature –40°C to 85°C	9.5			
$RL_{diff\_TX}$	Differential Return Loss						dB
		f = 1.25 GHz - 2.5 GHz,	Operating temperature 0°C to 85°C  Operating temperature –40°C to 85°C	6			
			5.5				
RL <sub>CM_TX</sub>	Common Mode Return Loss	f = 50 MHz – 2.5 GHz	10			dB	
I <sub>TX_SC</sub>	TX short circuit current	TX± shorted to GND		60	90	mA	
V <sub>TX_CM_DC</sub>	Transmitter DC common-mode voltage	Allowed DC CM voltage at T	2.1	2.65	3.1	V	
V <sub>TX_CM_AC2</sub>	TX AC common mode voltage at GEN II speed	- Max(V <sub>d+</sub> + V <sub>d-</sub> )/2 - Min(V <sub>d+</sub> -		26	100	mVpp	
V <sub>TX_CM_AC1</sub>	TX AC common mode voltage at GEN I speed	1012A(Vd+ + Vd-)/2 - 10111(Vd+ +	• v <sub>d</sub> _//∠		2	20	mV
V <sub>TX_CM_DeltaL0-L0s</sub>	Absolute Delta DC CM voltage during active and idle states	VTX_CM_DC [L0] - VTX_CM_DC [L	<sub>.0s]</sub>  , PS=L	0		100	mV
V <sub>TX_CM-DC-Line-</sub> Delta	Absolute Delta of DC CM voltage between D+ and D-	V <sub>TX_CM_DC-D+</sub> [L0] - V <sub>TX_CM_DC</sub>	C-D- [L0]	0		25	mV
$V_{TX\_idle\_diff-AC-p}$	Electrical idle differential peak output voltage	$ V_{TX-Idle-D+} - V_{TX-Idle-D-} $ HP fil	tered to remove any DC component	0	1	10	mVpp
$V_{TX\_idle\_diff\text{-DC}}$	DC Electrical idle differential output voltage	V <sub>TX_idle-D+</sub> - V <sub>TX_idle-D-</sub>   LP fil	tered to remove any AC component		3.5		mV
V <sub>detect</sub>	Voltage change to allow receiver detect	Positive voltage to sense rec	ceiver			600	mV
$t_R, t_F$	Output Rise/Fall time	DEx = NC, OS = NC (CH 0 a at the output; VID > 1000mV	and CH 1) 20%-80% of differential voltage (pp	30	53		ps
t <sub>RF_MM</sub>	Output Rise/Fall time mismatch	DEx = NC, OS = NC (CH 0 a at the output		1	20	ps	
T <sub>diff_LH</sub> , T <sub>diff_HL</sub>	Differential Propagation Delay		DEx = NC (CH 0 and CH 1). Propagation delay between 50% level at input and output. See Figure 6				
t <sub>idleEntry</sub> t <sub>idleExit</sub>	Idle entry and exit times	See Figure 7			4	6	ns
-	ON at GEN II Speed (under recomn	nenced operating conditions	)				
	,,	At point A in Figure 10 <sup>(2)</sup>			30	50	
T <sub>TX-TJ</sub> <sup>(1)</sup>	Total Jitter	At point B in Figure 10 <sup>(2)</sup>			25	80	ps pp
		At point A in Figure 10 <sup>(2)</sup>			16	30	
					10	55	ps pp

<sup>(1)</sup> Includes RJ at 10<sup>-12</sup>

<sup>(2)</sup> Refer to Figure 10 with ± K28.5 pattern at 5Gbps, -3.5dB DE from source AWG .



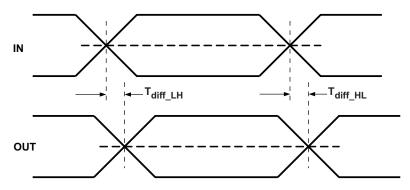


Figure 6. Propagation Delay

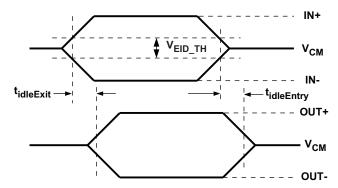


Figure 7. Idle Mode Exit and Entry Delay

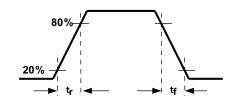


Figure 8. Output Rise and Fall Times

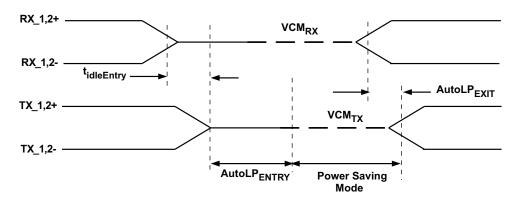


Figure 9. Auto Low Power Mode Timing (when enabled)



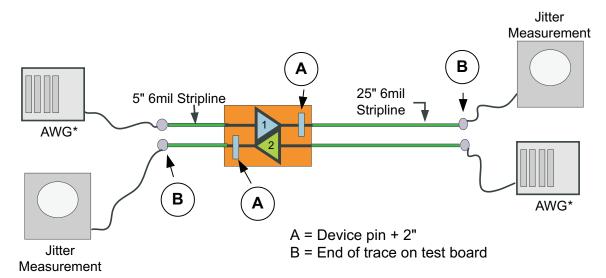


Figure 10. Jitter Measurement Setup

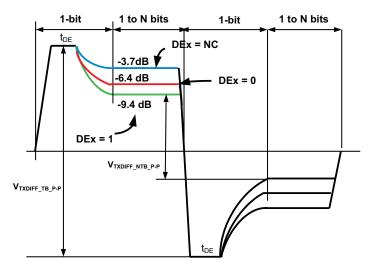


Figure 11. Output De-Emphasis Levels OSx = NC

## Typical Eye Diagram and Performance Curves at Output

Input Signal Characteristics: Data Rate = 5 Gbps,  $V_{ID}$  = 1000 mVpp, DE = -3.5 dB, Pattern = K28.5 Device Operating Conditions: VCC = 3.3 V, Temp = 25°C Device EQ settings (EQ/DE/OS) adjusted for best eye performance



### **Output Trace Length Held Constant and Input Trace Length Varied**

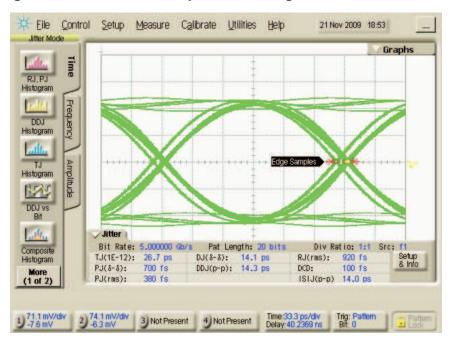


Figure 12. Input Trace = 4 Inches, 6 mil, and Measured at Output Trace = 4 Inches

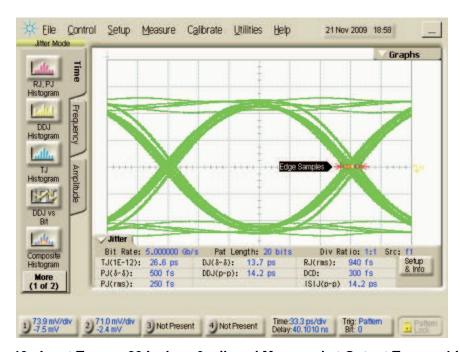


Figure 13. Input Trace = 20 Inches, 6 mil, and Measured at Output Trace = 4 Inches



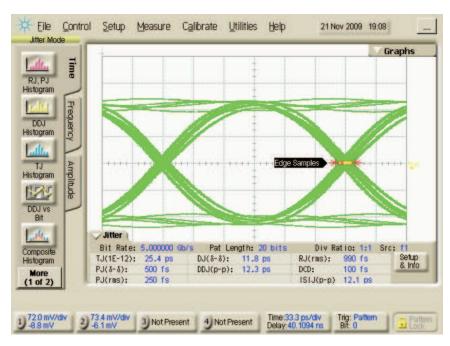


Figure 14. Input Trace = 32 Inches, 6 mil, and Measured at Output Trace = 4 Inches

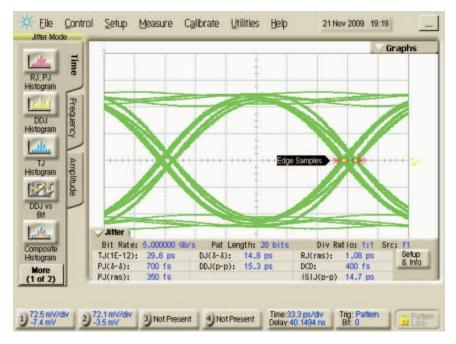


Figure 15. Input Trace = 44 Inches, 6 mil, and Measured at Output Trace = 4 Inches



## Variable Trace Lengths at Input and Output

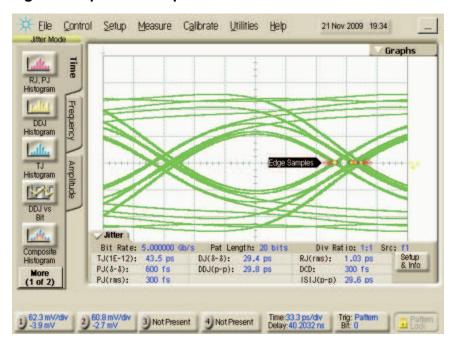


Figure 16. Input Trace = 28 Inches, 6 mil, and Measured at Output Trace = 24 Inches

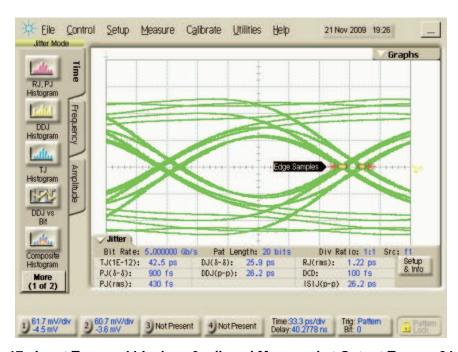


Figure 17. Input Trace = 44 Inches, 6 mil, and Measured at Output Trace = 24 Inches





## **REVISION HISTORY**

Ch	hanges from Original (May 2010) to Revision A	Page
•	Added Figure 4	7



## **PACKAGE OPTION ADDENDUM**

11-Apr-2013

#### PACKAGING INFORMATION

Orderable Device		Package Type	Package Drawing	Pins	Package Qty		Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Top-Side Markings	Samples
	(1)		Diawing		Qty	(2)		(3)		(4)	
SN65LVPE501RGER	ACTIVE	VQFN	RGE	24	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	LVPE501	Samples
SN65LVPE501RGET	ACTIVE	VQFN	RGE	24	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	LVPE501	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) Multiple Top-Side Markings will be inside parentheses. Only one Top-Side Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Top-Side Marking for that device.

**Important Information and Disclaimer:** The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 22-Jan-2015

## TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65LVPE501RGER	VQFN	RGE	24	3000	330.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
SN65LVPE501RGET	VQFN	RGE	24	250	180.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2

www.ti.com 22-Jan-2015



#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN65LVPE501RGER	VQFN	RGE	24	3000	367.0	367.0	35.0
SN65LVPE501RGET	VQFN	RGE	24	250	210.0	185.0	35.0

PLASTIC QUAD FLATPACK - NO LEAD

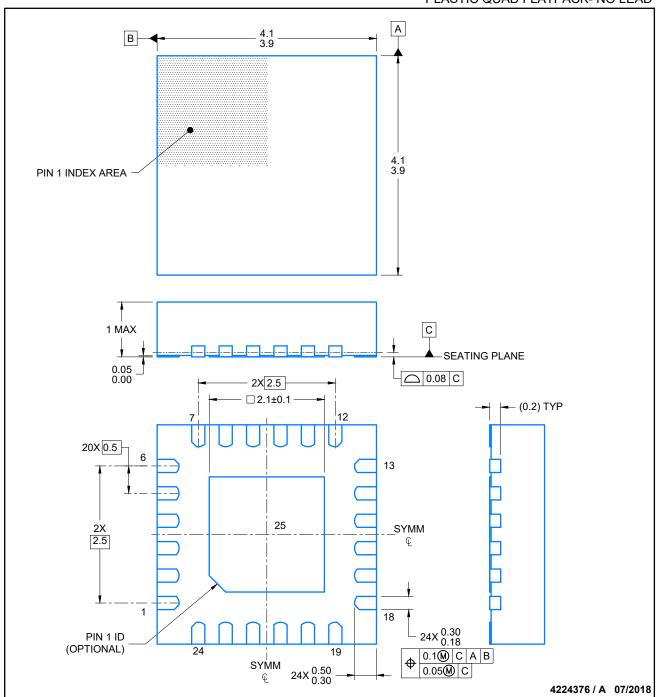


Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4204104/H



PLASTIC QUAD FLATPACK- NO LEAD

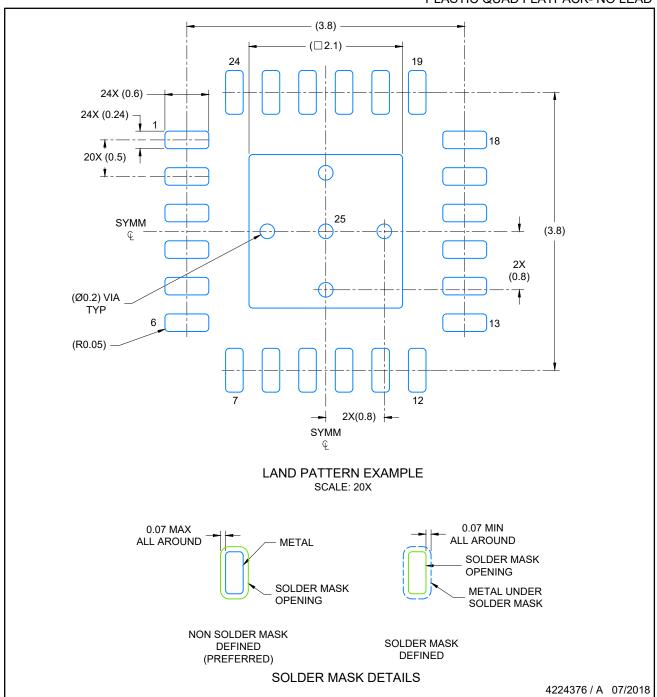


NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC QUAD FLATPACK- NO LEAD

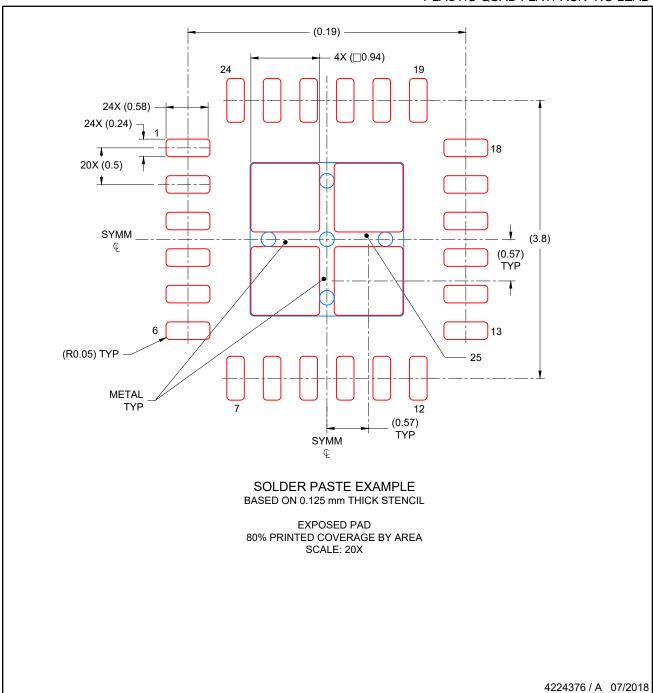


NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



PLASTIC QUAD FLATPACK- NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations..



#### **IMPORTANT NOTICE**

Texas Instruments Incorporated (TI) reserves the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete.

TI's published terms of sale for semiconductor products (http://www.ti.com/sc/docs/stdterms.htm) apply to the sale of packaged integrated circuit products that TI has qualified and released to market. Additional terms may apply to the use or sale of other types of TI products and services.

Reproduction of significant portions of TI information in TI data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such reproduced documentation. Information of third parties may be subject to additional restrictions. Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyers and others who are developing systems that incorporate TI products (collectively, "Designers") understand and agree that Designers remain responsible for using their independent analysis, evaluation and judgment in designing their applications and that Designers have full and exclusive responsibility to assure the safety of Designers' applications and compliance of their applications (and of all TI products used in or for Designers' applications) with all applicable regulations, laws and other applicable requirements. Designer represents that, with respect to their applications, Designer has all the necessary expertise to create and implement safeguards that (1) anticipate dangerous consequences of failures, (2) monitor failures and their consequences, and (3) lessen the likelihood of failures that might cause harm and take appropriate actions. Designer agrees that prior to using or distributing any applications that include TI products, Designer will thoroughly test such applications and the functionality of such TI products as used in such applications.

TI's provision of technical, application or other design advice, quality characterization, reliability data or other services or information, including, but not limited to, reference designs and materials relating to evaluation modules, (collectively, "TI Resources") are intended to assist designers who are developing applications that incorporate TI products; by downloading, accessing or using TI Resources in any way, Designer (individually or, if Designer is acting on behalf of a company, Designer's company) agrees to use any particular TI Resource solely for this purpose and subject to the terms of this Notice.

TI's provision of TI Resources does not expand or otherwise alter TI's applicable published warranties or warranty disclaimers for TI products, and no additional obligations or liabilities arise from TI providing such TI Resources. TI reserves the right to make corrections, enhancements, improvements and other changes to its TI Resources. TI has not conducted any testing other than that specifically described in the published documentation for a particular TI Resource.

Designer is authorized to use, copy and modify any individual TI Resource only in connection with the development of applications that include the TI product(s) identified in such TI Resource. NO OTHER LICENSE, EXPRESS OR IMPLIED, BY ESTOPPEL OR OTHERWISE TO ANY OTHER TI INTELLECTUAL PROPERTY RIGHT, AND NO LICENSE TO ANY TECHNOLOGY OR INTELLECTUAL PROPERTY RIGHT OF TI OR ANY THIRD PARTY IS GRANTED HEREIN, including but not limited to any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information regarding or referencing third-party products or services does not constitute a license to use such products or services, or a warranty or endorsement thereof. Use of TI Resources may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

TI RESOURCES ARE PROVIDED "AS IS" AND WITH ALL FAULTS. TI DISCLAIMS ALL OTHER WARRANTIES OR REPRESENTATIONS, EXPRESS OR IMPLIED, REGARDING RESOURCES OR USE THEREOF, INCLUDING BUT NOT LIMITED TO ACCURACY OR COMPLETENESS, TITLE, ANY EPIDEMIC FAILURE WARRANTY AND ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE, AND NON-INFRINGEMENT OF ANY THIRD PARTY INTELLECTUAL PROPERTY RIGHTS. TI SHALL NOT BE LIABLE FOR AND SHALL NOT DEFEND OR INDEMNIFY DESIGNER AGAINST ANY CLAIM, INCLUDING BUT NOT LIMITED TO ANY INFRINGEMENT CLAIM THAT RELATES TO OR IS BASED ON ANY COMBINATION OF PRODUCTS EVEN IF DESCRIBED IN TI RESOURCES OR OTHERWISE. IN NO EVENT SHALL TI BE LIABLE FOR ANY ACTUAL, DIRECT, SPECIAL, COLLATERAL, INDIRECT, PUNITIVE, INCIDENTAL, CONSEQUENTIAL OR EXEMPLARY DAMAGES IN CONNECTION WITH OR ARISING OUT OF TI RESOURCES OR USE THEREOF, AND REGARDLESS OF WHETHER TI HAS BEEN ADVISED OF THE POSSIBILITY OF SUCH DAMAGES.

Unless TI has explicitly designated an individual product as meeting the requirements of a particular industry standard (e.g., ISO/TS 16949 and ISO 26262), TI is not responsible for any failure to meet such industry standard requirements.

Where TI specifically promotes products as facilitating functional safety or as compliant with industry functional safety standards, such products are intended to help enable customers to design and create their own applications that meet applicable functional safety standards and requirements. Using products in an application does not by itself establish any safety features in the application. Designers must ensure compliance with safety-related requirements and standards applicable to their applications. Designer may not use any TI products in life-critical medical equipment unless authorized officers of the parties have executed a special contract specifically governing such use. Life-critical medical equipment is medical equipment where failure of such equipment would cause serious bodily injury or death (e.g., life support, pacemakers, defibrillators, heart pumps, neurostimulators, and implantables). Such equipment includes, without limitation, all medical devices identified by the U.S. Food and Drug Administration as Class III devices and equivalent classifications outside the U.S.

TI may expressly designate certain products as completing a particular qualification (e.g., Q100, Military Grade, or Enhanced Product). Designers agree that it has the necessary expertise to select the product with the appropriate qualification designation for their applications and that proper product selection is at Designers' own risk. Designers are solely responsible for compliance with all legal and regulatory requirements in connection with such selection.

Designer will fully indemnify TI and its representatives against any damages, costs, losses, and/or liabilities arising out of Designer's non-compliance with the terms and provisions of this Notice.